



Fabrication of nanofluidic devices based on isolated single walled carbon nanotube for coupling

ionic and electronic transport

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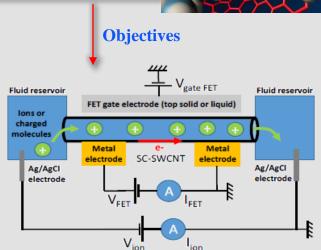


Introduction

Single-Walled Carbon Nanotubes (SWCNTs)

(SWCN18

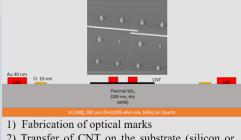
- Molecule confinementSelectivity
- Low friction
- Coupling electronic and ion transport



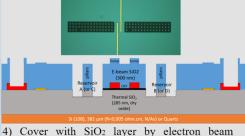
Study the influence of:

- 1) SWCNT edge functions on ionic transport
- 2) Electronic surface charges on ion transport through metallic-SWCNTs
- 3) Inner ion species in real time on the electronic transport of a semiconducting SWCNT Field Effect Transistors (FET)

Device fabrication



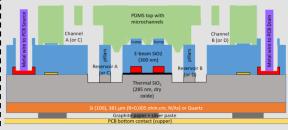
- 2) Transfer of CNT on the substrate (silicon or quartz)
- 3) Deposition of electrodes (Cr/Au/Cr) on the selected CNT by lithography followed by lift-off



- evaporation
- 5) Etch reservoirs and pad accesses and open the NTC by reactive ion etching

PDMS top with microchannels Channel Reservoir A (or C) Reservoir A (or C) E-brain 502 (300 nm) Cost (or C) (285 m, dy coide) Si (100), 351 µm (R-0,005 ohm.cm, N/As) or Quartz

6) Sealing the device by PDMS owing microfluidic channels. NB: for quartz substrate, a top gate electrode should be fabricated before PMDS sealing



- 7) Create electrical connections
- 8) Fill and measure ionic transport

Ionic measurements (primary results)

Silicon substrate:

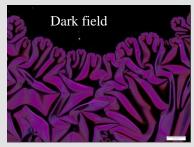
Photosensitive, electric leaks, high noise and periodic spikes, conductance = 100 pS at 1V for [KCl] = 0,1 M without CNT

Quartz substrate:

No electric leaks, low noise and no spikes, conductance = 1 pS at 1V for [KCl] = 0,1 M without CNT (to be considered as the baseline current)

Optimizations for device fabrication

- 1) Process of SWCNTs transfer on substrates (CAB instead of PMMA)
- 2) Cleaning process to eliminate totally the photoresist in lift-off for better surface quality (acetone + remover PG at 80 °C)
- 3) Adhesion improvement of the ${\rm SiO_2}$ layer (annealing after deposition at 200 °C for 1h)

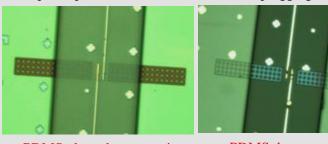




Without annealing

With annealing

- 4) Parameters calibration for reservoir etching and NTC opening
- 5) Required pressure to seal PDMS without plugging reservoirs



PDMS plugs the reservoirs

PDMS does not plug

Conclusion

- All steps of fabrication of the nanofluidic device are validated on silicon and quartz substrates
- Quartz are more suitable than silicon substrates for ionic measurements
- Such platform on quartz including CNT will be the next step for investigating coupling between ionic and electronic transport.